

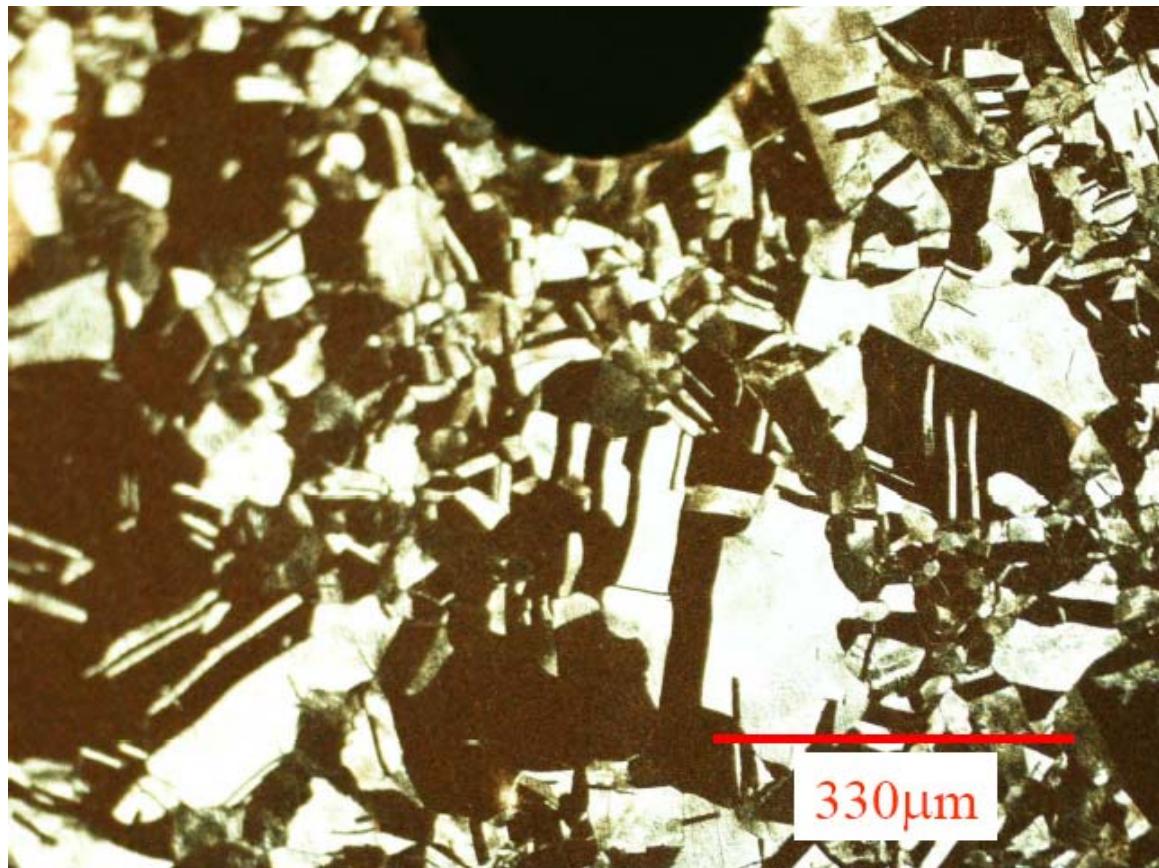
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AFM Measurements

Laboratory Experimental procedure

(1) Imaging of Cu grains with AFM topography.

An optical image of copper grains is shown below. Image a grain boundary with an AFM using either contact mode or a non-contacting mode.



(2) Measurement adhesion at different grain orientations

Go to two different grain surfaces and measure the adhesion forces as shown below.

